RELIABILITY DATA

LT1317/1766/1940/1944/1946/1947/1948/1949/1956/1961

8/12/2002

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS (1) AT +125°C	NUMBER OF (2) FAILURES
SOIC/SOT/MSOP	419	9740	0201	419.00	0
QFN	201	0102	0233	201.00	0
	620			620.00	0

• HIGHLY ACCELERATED STRESS TEST AT +131°C/85%RH

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICF HOURS (4) AT +85°C	NUMBER OF FAILURES
QFN	36	0112	0112	69.12	0
	36			69.12	0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	5,153	9812	0135	615.49	0
SSOP/TSSOP	200	0133	0137	24.33	0
QFN	944	0102	0112	343.96	0
	6,297			983.77	0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	24,812	9812	0149	2,750.63	0
SSOP/TSSOP	300	0133	0137	54.00	0
QFN	153	0112	0112	81.09	0
	25,265			2,885.72	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	2,988	9812	0145	415.40	0
SSOP/TSSOP	100	0136	0136	10.00	0
QFN	152	0112	0112	126.16	0
	3,240			551.56	0

(1) Assumes Activation Energy = 1.0 Electron Volts
(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 2.97 FITS
(3) Mean Time Between Failures in Years = 38,410
(4) Assumes 20X Acceleration from 85°C to +131°C
Note: 1 FIT = 1 Failure in One Billion Hours.